IN THE CLAIMS

- (Currently Amended) An integrated circuit package comprising:
 an integrated circuit die having an active surface; and
 a cooling fluid to directly contact and move laterally across the active surface.
- (Original) The integrated circuit package of claim 1 further comprising:
 an interposer coupled to the integrated circuit die.
- 3. (Original) The integrated circuit package of claim 2, wherein the interposer has a microchannel surface that allows the cooling fluid to flow between the interposer and the active surface of the integrated circuit die.
- 4. (Original) The integrated circuit package of claim 2 further comprising: a package substrate, wherein a first side of the interposer is coupled to the package substrate via solder bumps, and a second side of the interposer is coupled to the integrated circuit die via solder bumps.
- (Original) The integrated circuit package of claim 4 further comprising:
 an underfill material disposed substantially between the interposer and the package substrate.
- 6. (Original) The integrated circuit package of claim 1, wherein the integrated circuit die has a microchannel surface.

- 7. (Original) The integrated circuit package of claim 1 further comprising: a pump to circulate the cooling fluid.
- (Currently Amended) A method of forming an integrated circuit package comprising:

attaching an interposer to a package substrate;

attaching an integrated circuit die to the interposer, wherein the integrated circuit die includes an active region;

covering the package substrate, the integrated circuit die, and the interposer with a heat spreader to form an internal chamber;

filling the internal chamber with a cooling fluid, wherein the cooling fluid contacts a region between the interposer and the integrated circuit die and wherein the cooling fluid is to directly contact and move laterally across the active region.

- 9. (Original) The method of claim 8, wherein the filling of the internal chamber is done by pumping cooling fluid through a via in the package substrate.
- 10. (Previously Amended) A method of forming an integrated circuit package comprising:

attaching an interposer to a package substrate;
attaching an integrated circuit die to the interposer;
covering the package substrate, the integrated circuit die, and the interposer
with a heat spreader to form an internal chamber;

filling the internal chamber with a cooling fluid by pumping cooling fluid through a via in the package substrate and sealing the via after the internal chamber is filled.

11. (Previously Amended) A method of forming an integrated circuit package comprising:

attaching an interposer to a package substrate;

attaching an integrated circuit die to the interposer;

covering the package substrate, the integrated circuit die, and the interposer with a heat spreader to form an internal chamber;

filling the internal chamber with a cooling fluid by pumping cooling fluid through an inlet and sealing closed the inlet when the filling is complete.

12. (Currently Amended) A method of cooling an integrated circuit die within an integrated circuit package comprising:

providing power to the integrated circuit die; and moving a cooling fluid laterally across and in direct contact with an active surface of the integrated circuit die.

- 13. (Original) The method of claim 12, wherein the moving of the cooling fluid is performed by thermal convection.
- 14. (Original) The method of claim 12, wherein the moving of the cooling fluid is performed by a pump located inside of the integrated circuit package.

- 15. (Original) The method of claim 12, wherein the moving of the cooling fluid is performed by a pump located outside of the integrated circuit package.
- 16. (Original) The method of claim 12, wherein the cooling fluid changes phase by evaporating at a first location of the integrated circuit package and condensing at a second location of the integrated circuit package.
- 17. (Currently Amended) An integrated circuit package comprising:
 - a package substrate;
 - a first integrated circuit die having an active surface;
 - an interposer disposed between the package substrate and the first integrated circuit die, the interposer establishing electrical connectivity between the first integrated circuit die and the package substrate; and
 - a cooling fluid disposed between the first integrated circuit die and the interposer, wherein the cooling fluid is to directly contact and move laterally across the active surface.
- 18. (Original) The integrated circuit package of claim 17 further comprising:

 a heat spreader covering the package substrate, the first integrated circuit die,

 the cooling fluid, and the interposer.
- 19. (Original) The integrated circuit package of claim 18 further comprising:
 a heat sink coupled to the heat spreader.

- 20. (Original) The integrated circuit package of claim 18, wherein the first integrated circuit die has a microchannel surface in contact with the heat spreader, the microchannel surface allowing cooling fluid to flow across the microchannel surface.
- 21. (Cancelled)
- 22. (Original) The integrated circuit package of claim 17, wherein the interposer provides electrical functionality in addition to electrical connectivity.
- 23. (Original) The integrated circuit package of claim 22, wherein the interposer provides capacitance.
- 24. (Original) The integrated circuit package of claim 22, wherein the interposer comprises a second integrated circuit die.
- 25. (Original) The integrated circuit package of claim 24, wherein the second integrated circuit provides an optical to electrical interface for the first integrated circuit die.
- 26. (Original) The integrated circuit package of claim 17, wherein the interposer has a microchannel surface in contact with the active surface of the first integrated circuit die.
- 27. (Currently Amended) An integrated circuit package comprising:

 a integrated circuit die housed within a chamber, wherein the integrated circuit die includes an active region; and

a cooling fluid filling the chamber and to directly contact and move laterally across the active region of the integrated circuit die.

- 28. (Original) The integrated circuit package of claim 27 further comprising:

 a plurality of microchannels in a surface of the integrated circuit die.
- 29. (Original) The integrated circuit package of claim 28 further comprising: a pump located within the integrated circuit package to pump the cooling fluid through at least a portion of the plurality of microchannels.